

T-35-25

TOPAZ
SEMICONDUCTOR

SD217, SD219

**N-CHANNEL ENHANCEMENT-MODE
D-MOS POWER FET**

ORDERING INFORMATION

TO-206AF (TO-72) Package	SD217DE	SD219DE
Shorting Ring	SD217DE/R	SD219DE/R
Sorted Chips in Waffle Pack	SD217CHP	SD219CHP
Description	6.0 ohm, 25V V _{SB} = 15V min	6.0 ohm, 25V V _{SB} = 20V min

FEATURES

- CMOS Compatible Input
- Small Package, Standard Pin-Out
- TTL and CMOS Compatible Input
- Low Capacitance
- Peak Pulsed Current, 1 Amp min

APPLICATIONS

- ± 10V Analog Switch, SD219DE
- ± 7.5 Analog Switch, SD217DE
- High Speed, Medium Power, Switch Drivers
- Sample and Hold and Track and Hold
- A-to-D and D-to-A Converters

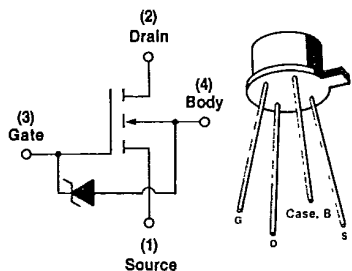
ABSOLUTE MAXIMUM RATINGS (T_A = + 25°C unless otherwise specified)

V _{DS} Drain-Source Voltage	+ 25V
V _{DB} Drain-Body Voltage	
SD217	+ 22.5V
SD219	+ 25V
V _{SD} Source-Drain Voltage	
SD217	+ 15V
SD219	+ 20V
V _{SB} Source-Body Voltage	
SD217	+ 22.5V
SD219	+ 25V
V _{GB} Gate-Body Voltage	+ 30V
V _{GS} Gate-Source Voltage	± 22.5V
V _{GD} Gate-Drain Voltage	± 22.5V
I _D Peak Pulsed Drain Current	+ 1.0A

I _D Continuous Drain Current (Note 1)	160mA
P _D Continuous Power Dissipation (Note 1)	
T _A = + 25°C (Free Air)	300mW
T _C = + 25°C (Infinite Heat Sink)	1.2W
Power Derating Factors (Note 1)	
Free Air	3.0mW/°C
Infinite Heat Sink	12mW/°C
Thermal Resistance (Note 1)	
Junction to Ambient	333°C/W
Junction to Case	83°C/W
O _{ja}	
O _{jc}	
T _{op} Operating Junction	
Temperature Range	-55 to + 125°C
T _{stg} Storage Temperature Range	-55 to + 150°C

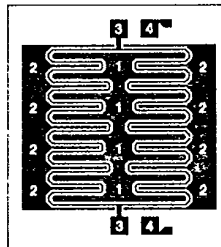
Note 1: Not applicable to chips. Final value depends on mounting.

SCHEMATIC DIAGRAM



PACKAGE DIMENSIONS (TO-72) TO-206AF
(See Package 3)

CHIP CONFIGURATION



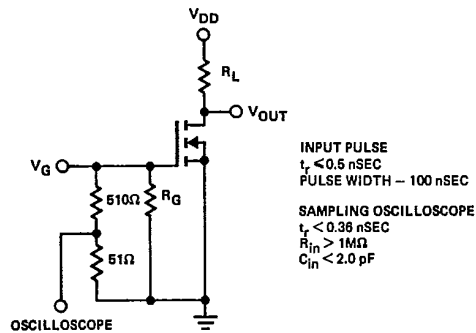
1—Drain 2—Source 3—Gate 4—Diode
Minimum bonding required. One Drain, One Source (left), One Source (right), One Gate. Bond Gate and Adjacent Diode to Common Point to Connect Protective Diode.
Size: .040 x .044 x .013 inch.
Body (Substrate) is backside contact.

ELECTRICAL CHARACTERISTICS (T_A = +25 °C unless otherwise specified)

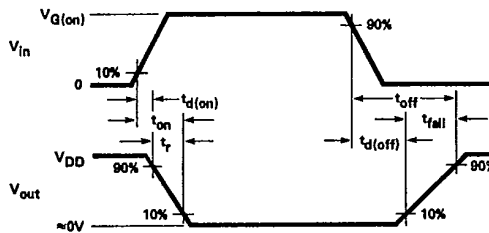
#	CHARACTERISTIC		MIN	TYP	MAX	UNITS	TEST CONDITIONS	
1	BV _{DS}	Drain-Source Breakdown Voltage	25	30		V	I _D = 10μA, V _{GS} = V _{BS} = 0	
2			15	20			I _D = 100nA, V _{GS} = V _{BS} = -5V	
3	BV _{SD}	Source-Drain Breakdown Voltage	SD217	15		V	I _S = 100nA, V _{GD} = V _{BD} = -5V	
4			SD219	20				
5	BV _{DB}	Drain-Body Breakdown Voltage	SD217	22.5		V	I _D = 100nA, V _{GB} = 0, Source Open	
6			SD219	25				
7	BV _{SB}	Source-Body Breakdown Voltage	SD217	22.5		V	I _S = 100nA, V _{GB} = 0, Drain Open	
8			SD219	25				
9	I _{D(off)}	Drain-Source OFF Leakage Current			100	nA	V _{DS} = 15V, V _{GS} = V _{BS} = -5V	
10		Source-Drain OFF Leakage Current			100		V _{SD} = 15V, V _{GD} = V _{BD} = -5V	
11	I _{GB}	Gate-Body ON Leakage Current			10	μA	V _{GB} = 30V, V _{GS} = V _{GD} = 22.5V	
12	V _{GS(th)}	Gate-Source Threshold Voltage	0.1		2.0	V	V _{DS} = V _{GS} , I _D = 10μA, V _{SB} = 0	
13	I _{D(on)}	Drain-Source ON Current (Note 1)	1.0			A	V _{DS} = V _{GS} = 10V, V _{SB} = 0	
14	r _{DS(on)}	Drain-Source ON Resistance (Note 1)			8.0	ohms	V _{GS} = 5.0V	I _D = 50mA
15					6.0		V _{GS} = 10V	V _{SB} = 0
16					6.0			I _D = 500mA
17	g _{fs}	Common-Source (Note 1) Forward Transconductance	100			mmhos	V _{DS} = 15V, I _D = 200mA	
18	C _(gs + gd + gb)	Gate Node Capacitance			30	pF	V _{DS} = 10V, V _{GS} = V _{BS} = -15V	
19		Drain-Node Capacitance			15			
20		Source Node Capacitance			40			
21		Reverse Transfer Capacitance			5.0			
22		t _{on}	Turn ON Time		2.0			4.0
23	t _{off}	Turn OFF Time		3.0	5.0		R _L = 133Ω, R _G = 51Ω	

Note 1: Pulse Test 80μSec, 1% Duty Cycle

SWITCHING TIMES TEST CIRCUIT



TEST WAVEFORMS



TYPICAL PERFORMANCE CHARACTERISTICS ($T_A = +25^\circ\text{C}$ unless otherwise specified)

